## BT151-500R

# SCR, 12 A, 15mA, 500 V, SOT78 Rev. 05 — 2 March 2009

**Product data sheet** 

#### **Product profile** 1.

### 1.1 General description

Planar passivated SCR (Silicon Controlled Rectifier) in a SOT78 plastic package.

#### 1.2 Features and benefits

- High reliability
- High surge current capability
- High thermal cycling performance

## 1.3 Applications

- Ignition circuits
- Motor control

- Protection Circuits
- Static switching

#### 1.4 Quick reference data

Table 1. **Quick reference** 

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{DRM}$	repetitive peak off-state voltage		-	-	500	V
$I_{T(AV)}$	average on-state current	half sine wave; T <sub>mb</sub> ≤ 109 °C; see <u>Figure 3</u>	-	-	7.5	Α
I <sub>T(RMS)</sub>	RMS on-state current	half sine wave; T <sub>mb</sub> ≤ 109 °C; see <u>Figure 1</u> ; see <u>Figure 2</u>	-	-	12	Α
Static ch	aracteristics					
I <sub>GT</sub>	gate trigger current	$V_D = 12 \text{ V; } T_j = 25 \text{ °C;}$ $I_T = 100 \text{ mA; see } \frac{\text{Figure 8}}{\text{ or } 100 \text{ mA;}}$	-	2	15	mA



## 2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	K	cathode		
2	Α	anode	mb	A → K
3	G	gate	205	G sym037
mb	mb	anode		
			SOT78 (TO-220AB;SC-46)	

## 3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
BT151-500R	TO-220AB; SC-46	plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB	SOT78

## 4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DRM}$	repetitive peak off-state voltage		-	500	V
$V_{RRM}$	repetitive peak reverse voltage		-	500	V
I <sub>T(AV)</sub>	average on-state current	half sine wave; T <sub>mb</sub> ≤ 109 °C; see <u>Figure 3</u>	-	7.5	Α
I <sub>T(RMS)</sub>	RMS on-state current	half sine wave; $T_{mb} \le 109 ^{\circ}\text{C}$ ; see Figure 1; see Figure 2	-	12	Α
dI <sub>T</sub> /dt	rate of rise of on-state current	$I_T = 20 \text{ A}$ ; $I_G = 50 \text{ mA}$ ; $dI_G/dt = 50 \text{ mA/}\mu\text{s}$	-	50	A/µs
I <sub>GM</sub>	peak gate current		-	2	Α
P <sub>GM</sub>	peak gate power		-	5	W
T <sub>stg</sub>	storage temperature		-40	150	°C
Tj	junction temperature		-	125	°C
I <sub>TSM</sub>	non-repetitive peak	half sine wave; $t_p = 8.3 \text{ ms}$ ; $T_{j(init)} = 25 \text{ °C}$	-	132	Α
	on-state current	half sine wave; $t_p = 10$ ms; $T_{j(init)} = 25$ °C; see Figure 4; see Figure 5	-	120	Α
l <sup>2</sup> t	I2t for fusing	t <sub>p</sub> = 10 ms; sine-wave pulse	-	72	$A^2s$
$P_{G(AV)}$	average gate power	over any 20 ms period	-	0.5	W
$V_{RGM}$	peak reverse gate voltage		-	5	V

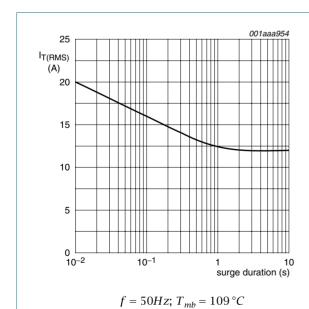


Fig 1. RMS on-state current as a function of surge duration; maximum values

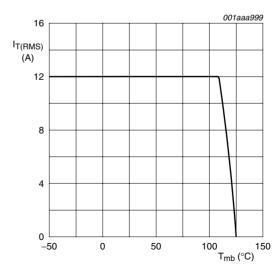


Fig 2. RMS on-state current as a function of mounting base temperature; maximum values

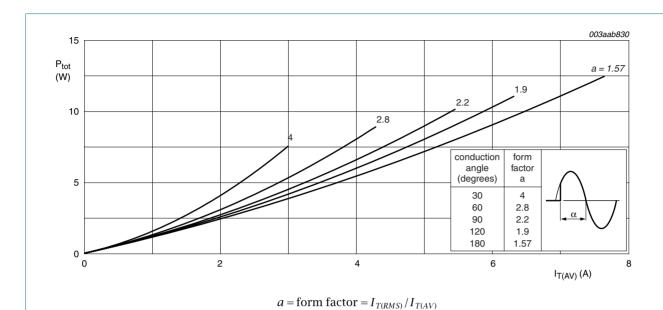


Fig 3. Total power dissipation as a function of average on-state current; maximum values

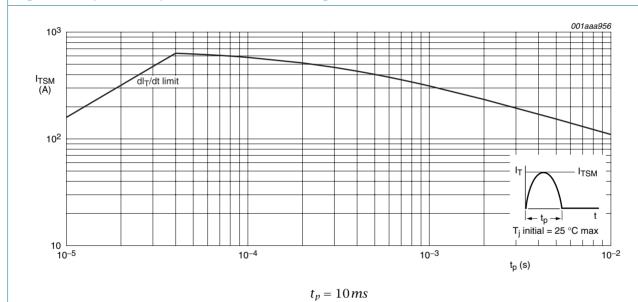


Fig 4. Non-repetitive peak on-state current as a function of pulse width for sinusoidal currents; maximum values

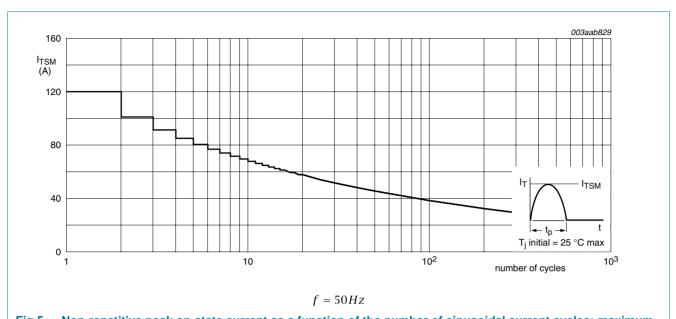
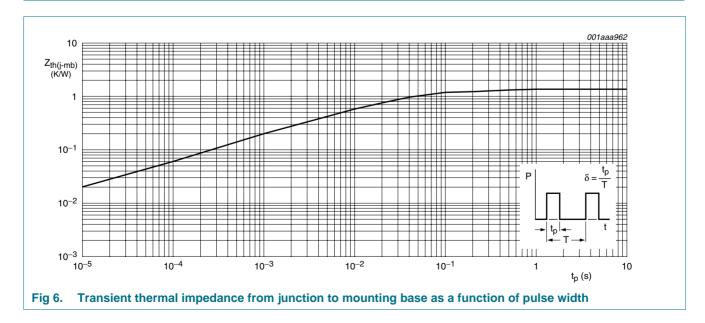


Fig 5. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values

### 5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base	see Figure 6	-	-	1.3	K/W
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient free air		-	60	-	K/W



## 6. Characteristics

Table 6. Characteristics

Citaracteristics					
Parameter	Conditions	Min	Тур	Max	Unit
aracteristics					
gate trigger current	$V_D = 12 \text{ V}; T_j = 25 \text{ °C}; I_T = 100 \text{ mA}; \text{ see}$ Figure 8	-	2	15	mA
latching current	$V_D = 12 \text{ V}; T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 9}}{}$	-	10	40	mΑ
holding current	$V_D = 12 \text{ V}; T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 10}}{\text{ or } 10}$	-	7	20	mΑ
on-state voltage	$I_T = 23 \text{ A}; T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 11}}{\text{Figure 11}}$	-	1.4	1.75	V
gate trigger voltage	$I_T$ = 100 mA; $V_D$ = 12 V; $T_j$ = 25 °C; see Figure 12	-	0.6	1.5	V
	$I_T$ = 100 mA; $V_D$ = 500 V; $T_j$ = 125 °C	0.25	0.4	-	V
off-state current	$V_D = 500 \text{ V}; T_j = 125 ^{\circ}\text{C}$	-	0.1	0.5	mA
reverse current	$V_R = 500 \text{ V}; T_j = 125 ^{\circ}\text{C}$	-	0.1	0.5	mA
characteristics					
rate of rise of off-state voltage	$V_{DM}$ = 335 V; $T_j$ = 125 °C; exponential waveform; gate open circuit	50	130	-	V/µs
	$V_{DM}$ = 335 V; $T_j$ = 125 °C; $R_{GK}$ = 100 Ω; exponential waveform; see Figure 7	200	1000	-	V/µs
gate-controlled turn-on time	$I_{TM} = 40 \text{ A}; V_D = 500 \text{ V}; I_G = 100 \text{ mA};$ $dI_G/dt = 5 \text{ A/}\mu\text{s}; T_j = 25 \text{ °C}$	-	2	-	μs
commutated turn-off time	$V_{DM}$ = 335 V; $T_j$ = 125 °C; $I_{TM}$ = 20 A; $V_R$ = 25 V; $(dI_T/dt)_M$ = 30 A/ $\mu$ s; $dV_D/dt$ = 50 V/ $\mu$ s; $R_{GK}$ = 100 $\Omega$	-	70	-	μs
	gate trigger current  latching current holding current on-state voltage gate trigger voltage  off-state current reverse current characteristics rate of rise of off-state voltage  gate-controlled turn-on time commutated turn-off	gate trigger current $V_D = 12 \text{ V}; T_j = 25 \text{ °C}; I_T = 100 \text{ mA}; \text{ see} \frac{\text{Figure 8}}{\text{Figure 8}}$ latching current $V_D = 12 \text{ V}; T_j = 25 \text{ °C}; \text{ see} \frac{\text{Figure 9}}{\text{Figure 10}}$ holding current $V_D = 12 \text{ V}; T_j = 25 \text{ °C}; \text{ see} \frac{\text{Figure 10}}{\text{Figure 10}}$ on-state voltage $I_T = 23 \text{ A}; T_j = 25 \text{ °C}; \text{ see} \frac{\text{Figure 11}}{\text{Figure 12}}$ gate trigger voltage $I_T = 100 \text{ mA}; V_D = 12 \text{ V}; T_j = 25 \text{ °C}; \text{ see} \frac{\text{Figure 12}}{\text{Figure 12}}$ $I_T = 100 \text{ mA}; V_D = 500 \text{ V}; T_j = 125 \text{ °C}$ off-state current $V_D = 500 \text{ V}; T_j = 125 \text{ °C}$ reverse current $V_D = 500 \text{ V}; T_j = 125 \text{ °C}$ characteristics  rate of rise of off-state voltage $V_{DM} = 335 \text{ V}; T_j = 125 \text{ °C}; \text{ exponential waveform}; \text{ gate open circuit}$ $V_{DM} = 335 \text{ V}; T_j = 125 \text{ °C}; \text{ R}_{GK} = 100 \Omega; \text{ exponential waveform}; \text{ see} \frac{\text{Figure 7}}{\text{Figure 7}}$ gate-controlled turn-on time $V_{DM} = 335 \text{ V}; T_j = 125 \text{ °C}; V_{TM} = 20 \text{ A}; V_{TM} = 25 \text{ °C}; V_{TM} = 20 \text{ A}; V_{TM} = 25 \text{ °C}; V_{TM} = 25 $	gate trigger current $V_D = 12 \text{ V}; T_j = 25 \text{ °C}; I_T = 100 \text{ mA}; \text{ see}$ - Figure 8  - Iatching current $V_D = 12 \text{ V}; T_j = 25 \text{ °C}; \text{ see Figure 9}$ - holding current $V_D = 12 \text{ V}; T_j = 25 \text{ °C}; \text{ see Figure 10}$ - on-state voltage $I_T = 23 \text{ A}; T_j = 25 \text{ °C}; \text{ see Figure 11}$ - gate trigger voltage $I_T = 100 \text{ mA}; V_D = 12 \text{ V}; T_j = 25 \text{ °C}; \text{ see}$ - Figure 12 $I_T = 100 \text{ mA}; V_D = 500 \text{ V}; T_j = 125 \text{ °C}$ 0.25 off-state current $V_D = 500 \text{ V}; T_j = 125 \text{ °C}$ - reverse current $V_D = 500 \text{ V}; T_j = 125 \text{ °C}$ - characteristics rate of rise of off-state voltage $V_{DM} = 335 \text{ V}; T_j = 125 \text{ °C}; \text{ exponential waveform}; \text{ gate open circuit}$ $V_{DM} = 335 \text{ V}; T_j = 125 \text{ °C}; R_{GK} = 100 \Omega; \text{ exponential waveform}; \text{ see Figure 7}$ gate-controlled turn-on time $I_{TM} = 40 \text{ A}; V_D = 500 \text{ V}; I_G = 100 \text{ mA}; \text{ commutated turn-off time}$ $V_{DM} = 335 \text{ V}; T_j = 125 \text{ °C}; I_{TM} = 20 \text{ A}; \text{ commutated turn-off time}$ $V_{DM} = 335 \text{ V}; T_j = 125 \text{ °C}; I_{TM} = 20 \text{ A}; \text{ commutated turn-off time}$ $V_{DM} = 335 \text{ V}; T_j = 125 \text{ °C}; I_{TM} = 20 \text{ A}; \text{ commutated turn-off time}$ $V_{DM} = 335 \text{ V}; T_j = 125 \text{ °C}; I_{TM} = 20 \text{ A}; \text{ commutated turn-off time}$ $V_{DM} = 335 \text{ V}; T_j = 125 \text{ °C}; I_{TM} = 20 \text{ A}; \text{ commutated turn-off time}$ $V_{DM} = 335 \text{ V}; T_j = 125 \text{ °C}; I_{TM} = 20 \text{ A}; \text{ commutated turn-off time}$ $V_{DM} = 335 \text{ V}; T_j = 125 \text{ °C}; I_{TM} = 20 \text{ A}; \text{ commutated turn-off time}$ $V_{DM} = 335 \text{ V}; T_j = 125 \text{ °C}; I_{TM} = 20 \text{ A}; \text{ commutated turn-off time}$ $V_{DM} = 335 \text{ V}; T_j = 125 \text{ °C}; I_{TM} = 20 \text{ A}; \text{ commutated turn-off time}$ $V_{DM} = 335 \text{ V}; T_j = 125 \text{ °C}; I_{TM} = 20 \text{ A}; \text{ commutated turn-off time}$ $V_{DM} = 335 \text{ V}; T_j = 125 \text{ °C}; I_{TM} = 20 \text{ A}; \text{ commutated turn-off time}$ $V_{DM} = 335 \text{ V}; T_j = 125 \text{ °C}; I_{TM} = 20 \text{ A}; \text{ commutated turn-off time}$ $V_{DM} = 335 \text{ V}; T_j = 125 \text{ °C}; I_{TM} = 20 \text{ A};  $	$ \begin{array}{llllllllllllllllllllllllllllllllllll$	$\begin{array}{llllllllllllllllllllllllllllllllllll$

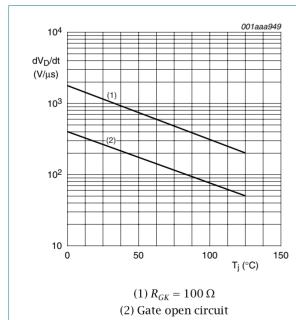


Fig 7. Critical rate of rise of off-state voltage as a function of junction temperature; minimum values

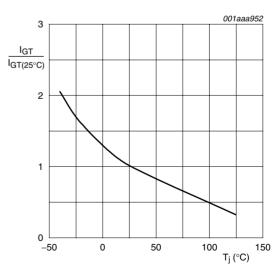
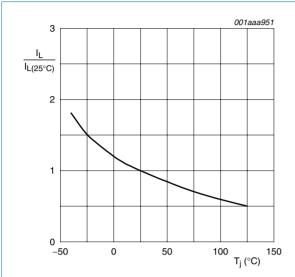


Fig 8. Normalized gate trigger current as a function of junction temperature



Normalized latching current as a function of Fig 9. junction temperature

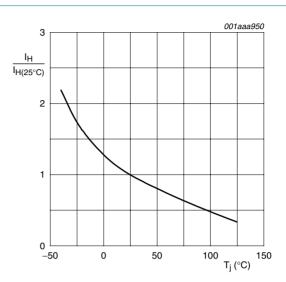
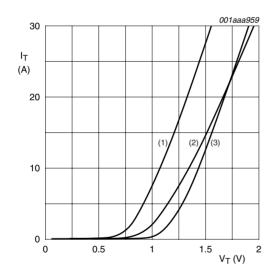


Fig 10. Normalized holding current as a function of junction temperature



 $V_0 = 1.06 \ V; R_s = 0.0304 \ \Omega$ (1)  $T_i = 150$  °C; typical values (2)  $T_i = 150$  °C; maximum values (3)  $T_i = 25$  °C; maximum values

Fig 11. On-state current as a function of on-state voltage

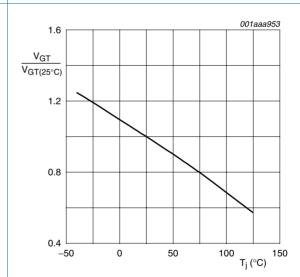


Fig 12. Normalized gate trigger voltage as a function of junction temperature

## 7. Package outline

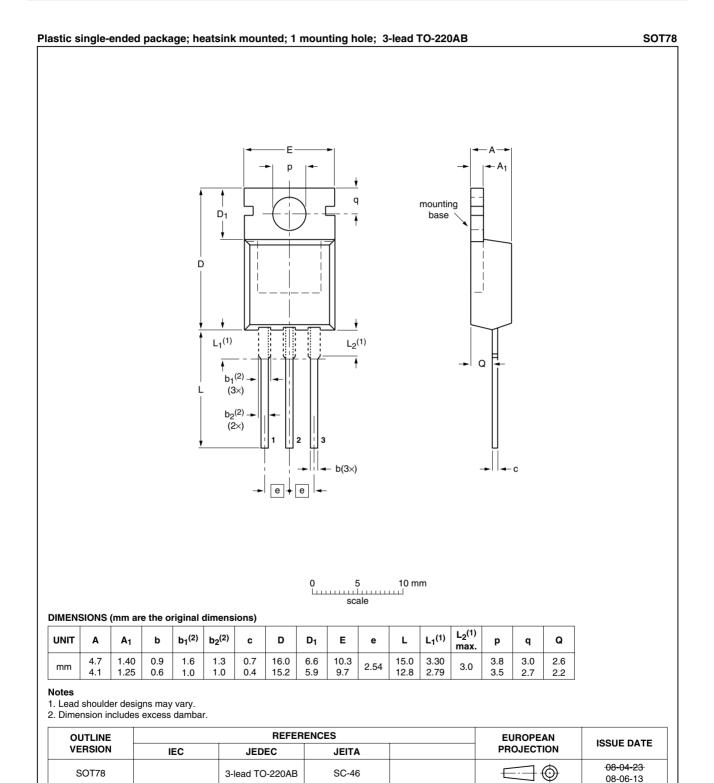


Fig 13. Package outline SOT78 (TO-220AB)

BT151-500R\_5

9 of 11

SCR, 12 A, 15mA, 500 V, SOT78

## **Revision history**

#### Table 7. **Revision history**

**Product data sheet** 

Document ID	Release date	Data sheet status	Change notice	Supersedes
BT151-500R_5	20090302	Product data sheet	-	BT151_SER_L_R_4
Modifications:	Package ou	utline updated.		
	<ul> <li>Type numb</li> </ul>	er BT151-500R separated	from data sheet BT151	_SER_L_R_4.
BT151_SER_L_R_4	20061023	Product data sheet	-	BT151_SERIES_3
BT151_SERIES_3 (9397 750 13159)	20040607	Product specification	-	BT151_SERIES_2
BT151_SERIES_2	19990601	Product specification	-	BT151_SERIES_1
BT151_SERIES_1	19970901	Product specification	-	-

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Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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- [2] The term 'short data sheet' is explained in section "Definitions"
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## 11. Contents

1	Product profile	1
1.1	General description	1
1.2	Features and benefits	1
1.3	Applications	1
1.4	Quick reference data	1
2	Pinning information	2
3	Ordering information	2
4	Limiting values	3
5	Thermal characteristics	5
6	Characteristics	6
7	Package outline	8
8	Revision history	9
9	Legal information	10
9.1	Data sheet status	10
9.2	Definitions	10
9.3	Disclaimers	10
9.4	Trademarks	10
10	Contact information	10

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